Special Issue on Surface Characterization Techniques

Call for Papers

Characterization of a solid surface requires the use of analytical techniques which are able to detect very low quantity of material and to discriminate the information originating from the surface from that coming from the bulk. Usually, information is searched on the topography of the surface, its structure, its elementary and chemical composition and the quantitative distribution of the elements (laterally as well as in function of depth). The improvement of ultra-high vacuum technology and the automation of data acquisition and reduction in the past four decades have lead to an explosion in the development of surface analytical probes. Four of the most widely used surface analysis techniques are described in this chapter: Auger electron spectroscopy, X-ray photoelectron spectroscopy, secondary ion mass spectrometry and atomic force microscopy. For all of them, the basic physical background is given, together with the major features of the technique and its applications.

In this special issue, we are going to invite front-line researchers and authors to submit original research and review articles that explore **Surface Characterization Techniques**.

Authors should read over the journal's Author's Guidelines carefully before submission. Prospective authors should submit an electronic copy of their complete manuscript through the journal at Paper Submission System.

Please kindly notice that the "Special Issue'' under your manuscript title is supposed to be specified and the research field "Special Issue — **Surface Characterization Techniques**" should be chosen during your submission.

According to the following timetable:

Submission Deadline	July 23rd, 2013
Publication Date	September 2013

Guest Editor:

Dr.**Bouzid Menaa**; **Fluorotronics Inc., USA**

For further questions or inquiries
Please contact Editorial Assistant at
jsemat@scirp.org